

<b>Notice of References Cited</b>	Application/Control No. 10/605,478	Applicant(s)/Patent Under Reexamination CHU ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,596,654	07-2003	Bayman et al.	438/788
	B	US-2004/0126952	07-2004	Gondhalekar et al.	438/200
	C	US-2004/0079728	04-2004	Mungekar et al.	216/067
	D	US-2004/0146661	07-2004	Kapoor et al.	427/569
	E	US-6,740,601	05-2004	Tan et al.	438/771
	F	US-6,589,854	07-2003	Liu et al.	438/435
	G	US-2003/0087506	05-2003	Kirchhoff, Markus	438/424
	H	US-2003/0207580	11-2003	Li et al.	438/700
	I	US-2004/0079632	04-2004	Ahmad et al.	204/192.3
	J	US-2004/0115898	06-2004	Moghadam et al.	438/435
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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